

AMENDMENTS TO THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application:

LISTING OF CLAIMS:

Claim 1 (canceled).

Claim 2 (previously presented): The probe card claimed in Claim 8, wherein a first reinforcing plate that comes in contact with the substrate body is arranged at the other side of the substrate body.

Claim 3 (original): The probe card claimed in Claim 2, wherein the support member is attached to the first reinforcing plate via a spacer inserted into a bore hole formed on the substrate body.

Claim 4 (original): The probe card claimed in Claim 2, wherein a heat-conductive sheet is provided between the substrate body and the first reinforcing plate.

Claim 5 (previously presented): The probe card claimed in Claim 3, wherein heat-conductive sheets are provided respectively between the substrate body and the first reinforcing

plate, between the spacer and the first reinforcing plate and between the spacer and the support member.

Claim 6 (original): The probe card claimed in any one of Claims 2 to 5, wherein a screw serving as the parallelism adjusting means is threadedly secured to the first reinforcing plate so as to cause its leading edge to be in contact with the contactor unit via a hole formed on the substrate body, while a second reinforcing plate is attached to the first reinforcing plate for covering the hole formed on the first reinforcing plate and a screw is threadedly secured to the second reinforcing plate so as to cause its leading edge to be in contact with a position of the substrate body above the contactor unit via the hole.

Claim 7 (original): The probe card claimed in Claim 6, wherein a heat-conductive sheet is provided between the first reinforcing plate and the second reinforcing plate.

Claim 8 (currently amended): A probe card used for performing an electrical test of a subject to be tested that is a semiconductor device or the like and comprising:

a substrate body;

a contactor unit, one surface thereof oriented to face one surface of the substrate body and the other surface of the contactor unit is provided with a plurality of contactors capable of electrical contact with electrodes of the subject to be tested;

~~an interposer for establishing an electrical connection between said substrate body and
said contactor unit;~~

supporting means for supporting the contactor unit with elastic force; and

a plurality of parallelism adjusting means provided with the substrate body and for
adjusting a degree of parallelism of the contactor unit, wherein

said contactor unit is provided with a flange section ~~is provided~~ at an outside section of
~~the contactor unit thereof,~~

wherein the supporting means is configured to include a support member with a flange
~~section provided at an inside section thereof and arranged to face the flange section of the~~
~~contactor unit in a vertical direction and include a~~ and a coil spring, the support member being
provided in the substrate body and having a flange section facing said flange section of the
contactor unit at a greater distance than the contactor unit from the substrate body, the coil spring
being interposed between said flange section of the support member and said flange section of
the contactor unit for urging the contactor unit toward the substrate body, and

wherein said parallelism adjusting means pushes a surface of the contactor unit in a
manner to get away from the substrate body against the urging force applied by the coil spring to
thereby adjust a spacing between the contactor unit and the substrate body.